INVESTIGATION OF NMR-BASED SURFACE AREA MEASUREMENT AS A QUALITY MONITOR FOR NANOPARTICLE SILICA ABRASIVES

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Good Control of Silica Particle Size and Contamination is Important for CMP

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- Big nanoparticles permanently damage transistors during polishing
- Small nanoparticles don't polish well and are harder to wash off in later stages
- Chemical contamination of slurries may damage transistors (for example, iron)
- Improper shipment and/or storage may alter slurries' properties and be undetected

Xigo Area Quant Has a Number of Benefits as a Quality Control Instrument

Benefits

- Uses wet samples with 1-60% concentration
- Measures relaxation rate that is directly proportional to surface area
- Able to perform fast (less than 1 min) and continuous measurements

Picture (xigonanotools.com)



NMR Equipment



1. Short radio frequency pulse excited the coil at ~14 MHz.

2. Produced magnetic field changes the orientation of protons' spins.

3. As the spins relax and realign with static magnetic field B_0 , a decaying voltage is produced in the coil – "free induction decay".

Sample T₂ (transverse) Graph

4. A combination of specific pulse sequences allows to determine sample's T_1 or T_2 relaxation times.



http://www.sprawls.org/mripmt/MRI04/index.html



Wikipedia.org

NMR Relaxation Time of H Near Particle Surface is Very Short

Due to constrained mobility H in water molecules around nanoparticles relax at faster rate compared to H in free water <u>Data Analysis:</u>

Relaxation rate: R = 1/T

$$\mathbf{R}_{\mathrm{av}} = \mathbf{k}_{\mathrm{a}} \mathbf{S} \boldsymbol{\psi}_{\mathrm{p}} + \mathbf{R}_{\mathrm{b}}$$

- R_{av} average relaxation rate (the reading)
- \square R_b bulk relaxation rate
- k_a specific surface relaxivity
- S total surface area of particles per unit weight
- ψ_p volume fraction of particles

Research Questions

- Does temperature affect the measurements?
- How reliable and stable are the measurements?
- Does the signal depend on the chemistry of the solution? Is k_a affected by background electrolyte concentration?
- What is the lowest Fe detectability limit? Does it depend on the type iron compound and phase?

1. Temperature Dependence of T₂



- □ For every degree C, T₂ changes by 2%
- Temperature controlled cell is needed for better measurements
- Inline metrology may not be feasible if significant temperature swings are present

2. Precision of "Fast" Measurements



Small deviations in T_2 signal when the measurements are taken within minutes apart

2. Stability of T₂ Measurements Over Time



- □ For slow aggregation induced by low salt, T₂ does not show a systematic change when the size increases by a few nanometers
- □ Large fluctuations in T₂ signal are seen
- Presence of significant outliers is detected over timescale of several hours

3. Chemistry: effect on k_a



□ For TM-50, k_a varied by about 1% as electrolyte (KNO₃) was increased.

3. Chemistry: effect on calculated area



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For given nanoparticles for every 0.1 wt% [NH₃/NH₄⁺] added

- T_2 goes up by 24 ms
- **Calculated** surface area of the particles appears to be smaller by 1.3 m²/g

The effect of ammonia on T_2 and indicated surface area may be substantial depending on the specs

4. Detection of Insoluble Iron (Fe_xO_y) at ~10⁻⁵ M



Mass concentration of Fe_xO_y added

Insoluble iron oxide can be detected at low concentrations of ~10⁻⁵ M



4. Detection of Soluble Iron (FeCl₃) at ~10⁻⁴ M



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 Soluble iron salts can be detected at low concentrations of ~10⁻⁴ M
Detectability limit may depend on silica solids loading

Summary

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- □ Reliable measurements require temperature control
- □ Effects of chemistry on relaxation rate and indicated surface area can be small but significant depending on product specifications
- NMR equipment is very good at quickly detecting iron contamination at levels of 10-100 ppm
- $\hfill\square$ More investigation is needed of precision and deviations in T_2 signal
 - **Bottom line: the technique is promising but more work is needed to reduce measurement variation**

¹⁶ Thank you for your attention!

Questions?